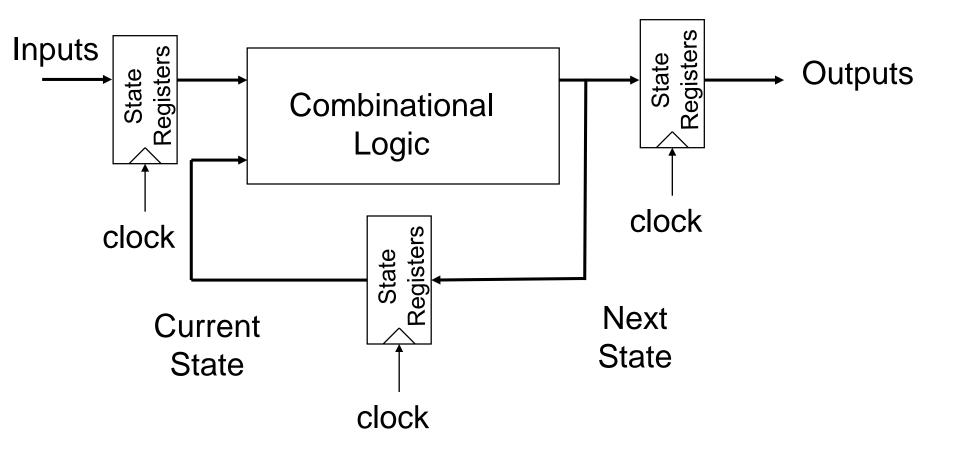
Electronics Systems

Timing Issues

Luca Fanucci

[Adapted from Rabaey's *Digital Integrated Circuits*, Second Edition, ©2003 J. Rabaey, A. Chandrakasan, B. Nikolic]

Sequential Logic



Static vs Dynamic Storage

Static storage

- preserve state as long as the power is on
- have positive feedback (regeneration) with an internal connection between the output and the input
- useful when updates are infrequent (clock gating)

Dynamic storage

- store state on parasitic capacitors
- only hold state for short periods of time (milliseconds)
- require periodic refresh
- usually simpler, so higher speed and lower power

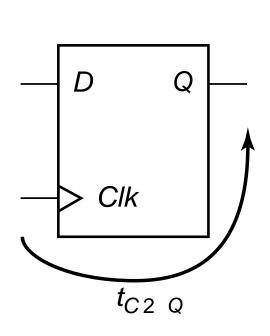
Latches vs Flipflops

Latches

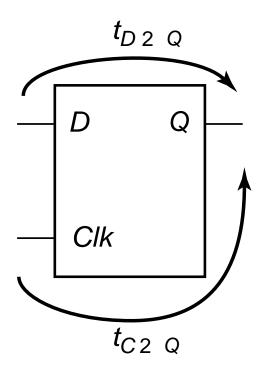
- level sensitive circuit that passes inputs to Q when the clock is high (or low) - transparent mode
- input sampled on the falling edge of the clock is held stable when clock is low (or high) - hold mode

- Flipflops (edge-triggered)
 - edge sensitive circuits that sample the inputs on a clock transition
 - positive edge-triggered: 0 → 1
 - negative edge-triggered: 1 → 0
 - built using latches (e.g., master-slave flipflops)

Characterizing Timing



Register



Latch

Timing Classifications

Synchronous systems

- All memory elements in the system are simultaneously updated using a globally distributed periodic synchronization signal (i.e., a global clock signal)
- Functionality is ensure by strict constraints on the clock signal generation and distribution to minimize
 - Clock skew (spatial variations in clock edges)
 - Clock jitter (temporal variations in clock edges)

Asynchronous systems

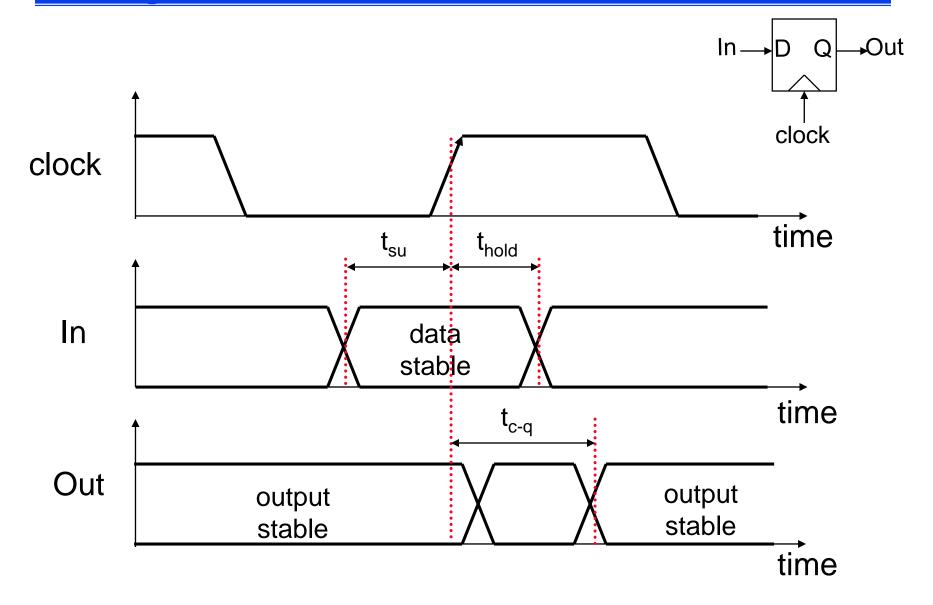
- Self-timed (controlled) systems
- No need for a globally distributed clock, but have asynchronous circuit overheads (handshaking logic, etc.)

Hybrid systems

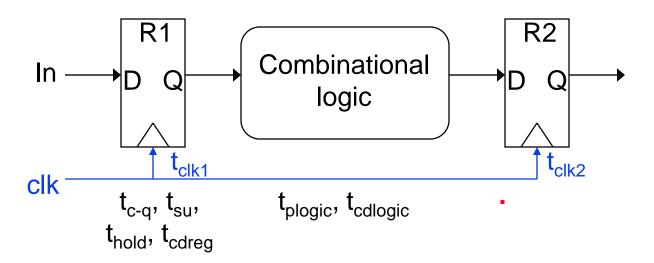
- Synchronization between different clock domains
- Interfacing between asynchronous and synchronous domains

GALS

Timing Metrics



Review: Synchronous Timing Basics

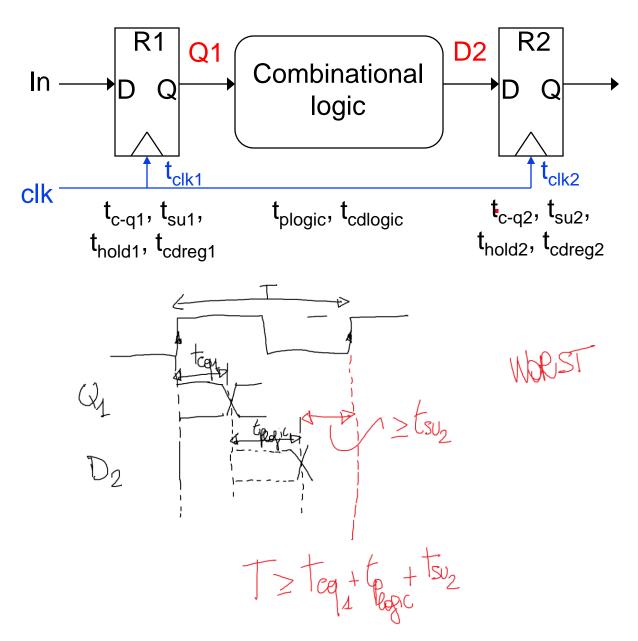


 \Box Under ideal conditions (i.e., when $t_{clk1} = t_{clk2}$)

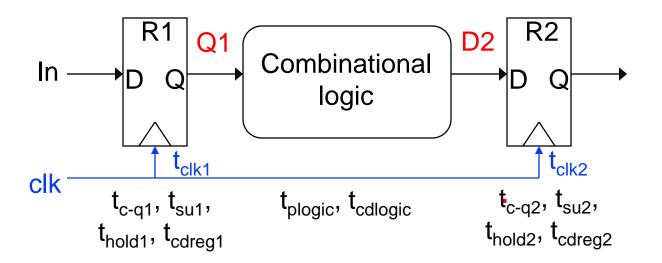
$$T \ge t_{c-q} + t_{plogic} + t_{su}$$
 $t_{hold} \le t_{cdlogic} + t_{cdreg}$
 $T \ge t_{c-q} + t_{plogic} + t_{su}$
 $T = T + t_{plogic} + t_{su}$
 $T = T + t_{plogic} + t_{su}$

the contamination delay is the minimum amount of time from when an input changes until any output starts to change its value. This change in value does not imply that the value has reached a stable condition.

Set-Up Time Violation

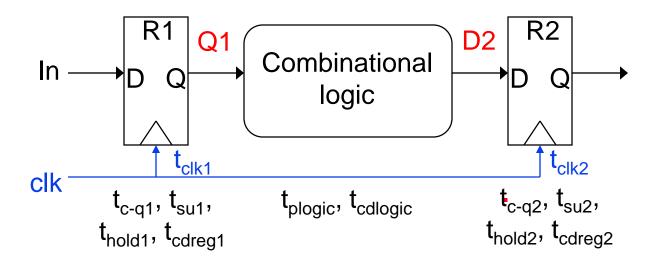


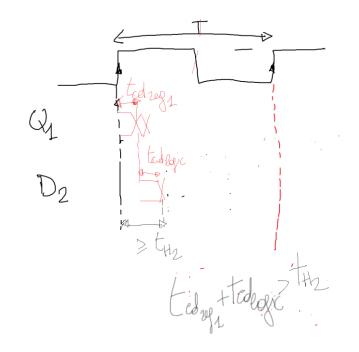
Set-Up Time Violation



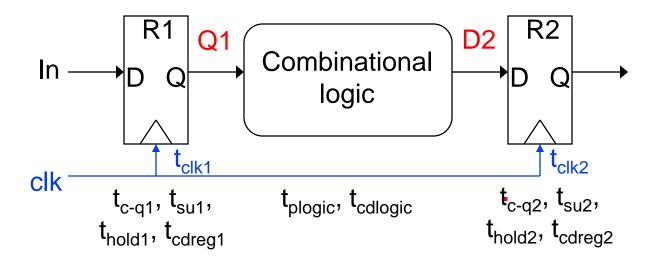
$$T \ge t_{c-q1} + t_{plogic} + t_{su1}$$

Hold Time Violation



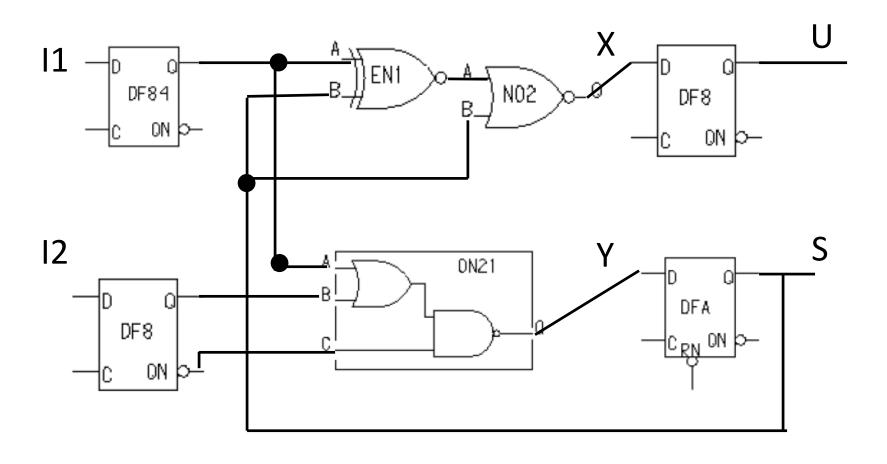


Hold Time Violation



$$t_{hold2} \le t_{cdlogic} + t_{cdreg1}$$

Example for evaluating minimum Clock Period

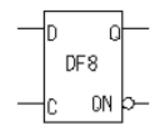


$$T \ge t_{c-q} + t_{plogic} + t_{su}$$

DF8 is a static, master-slave D flip-flop with 1x drive strength.

Truth Table

С	D	Q	QN
1	0	0	1
1	1	1	0



Capacitance

Pin	Cap [pF]
С	0,010
D	0,010

Area

0.423 mils² 273 µm²

Power

1.736 µW/MHz

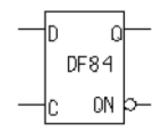
Load	0,015	0,020	0,035
Delay C->Q	0,75	0,80	1,0
Delay C->QN	0,74	0,79	0,99

	Setup	Hold
D->C	0,17	0,04

DF84 is a static, master-slave D flip-flop with 4x drive strength.

Truth Table

С	D	Q	QN
1	0	0	1
↑	1	1	0



Capacitance

Pin	Cap [pF]	
С	0,010	
D	0,010	

Area

0.48 mils² 310 µm²

Power

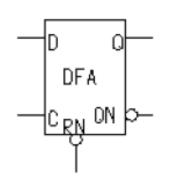
 $2.88 \mu W/MHz$

Load	0,015	0,020	0,035
Delay C->Q	0,65	0,70	0,90
Delay C->QN	0,64	0,69	0,89
	Setup	Hold	
D->C	0,17	0,04	

DFA is a static, master-slave D flip-flop with 1x drive strength. RESET is asynchronous and active low.

Truth Table

С	D	RN	Q	QN
1	0	1	0	1
↑	1	1	1	0
X	X	0	0	1



Capacitance

Pin	Cap [pF]	
С	0,010	
D	0,010	
RN	0,020	

Area

0.536 mils ²	
346 µm²	

RN->C

	Setup	Hold
D->C	0,16	0,04

0,73

1.773 µW/MHz

Power

Load	0,015	0,020	0,035
Delay C->Q	0,84	0,90	1,2
Delay C->QN	0,84	0,89	1,1

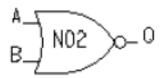
0,01

Timing Issues .17

NO2 is a 2-input NOR gate with 1x drive strength.

Truth Table

Α	В	Q
0	0	1
X	1	0
1	Χ	0



Capacitance

Pin	Cap [pF]	
Α	0,015	
В	0,015	

Area

0.085 mils² 55 µm²

Power

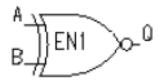
 $0.422~\mu W/MHz$

Load [pF]	0,010	0,015	0,020
Delay A->Q [ns]	0,13	0,24	0,31
Delay B->Q [ns]	0,11	0,23	0,29

EN1 is a 2-input EXCLUSIVE-NOR (XNOR) gate with 1x drive strength.

Truth Table

Α	В	Q
0	0	1
0	1	0
1	0	0
1	1	1



Capacitance

Pin	Cap [pF]	
Α	0,020	
В	0,020	

Area

0.169 mils² 109 µm²

Power

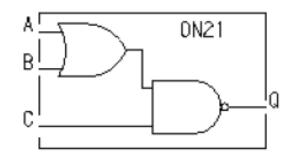
0.576 µW/MHz

Load [pF]	0,010	0,015	0,020
Delay A->Q [ns]	0,28	0,35	0,40
Delay B->Q [ns]	0,27	0,33	0,39

ON21 is an OR / NAND circuit providing the logical function Q = NOT [(A+B).C].

Truth Table

Α	В	С	Q
0	0	Χ	1
X	X	0	1
X	1	1	0
1	X	1	0



Capacitance

Pin	Cap [pF]
Α	0,015
В	0,015
С	0,015

Area

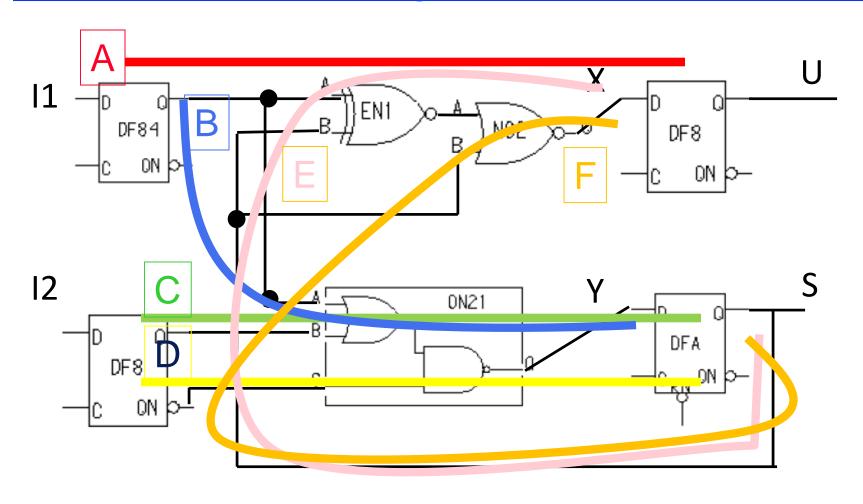
0.141 mils² 91 µm²

Power

0.446 µW/MHz

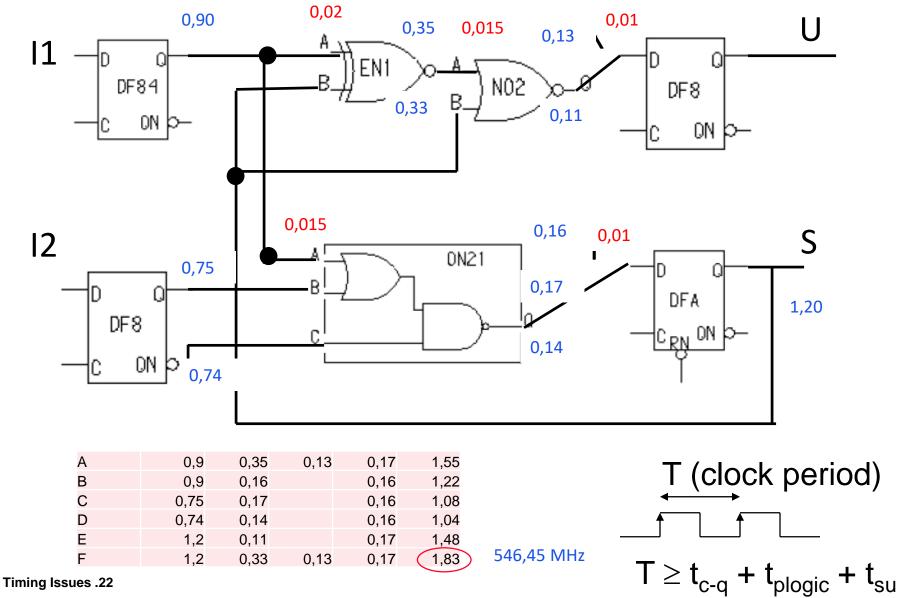
Load [pF]	0,010	0,015	0,020
Delay A->Q [ns]	0,16	0,23	0,34
Delay B->Q [ns]	0,17	0,24	0,35
Delay C->Q [ns]	0,14	0,20	0,30

Example for evaluating minimum Clock Period

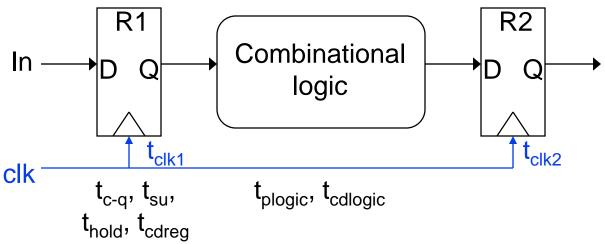


$$T \ge t_{c-q} + t_{plogic} + t_{su}$$

Example for evaluating minimum Clock Period



Review: Synchronous Timing Basics



□ Under ideal conditions (i.e., when $t_{clk1} = t_{clk2}$)

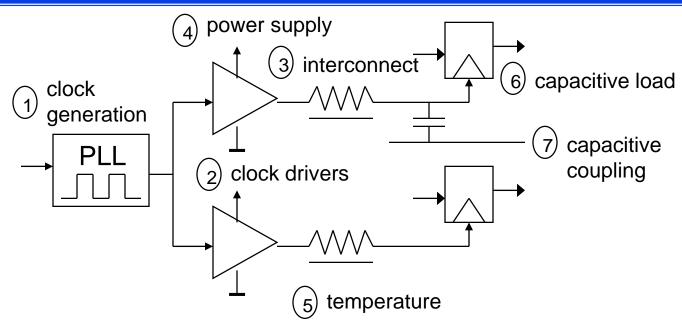
$$T \ge t_{c-q} + t_{plogic} + t_{su}$$

 $t_{hold} \le t_{cdlogic} + t_{cdreg}$

- Under real conditions, the clock signal can have both spatial (clock skew) and temporal (clock jitter) variations
 - skew is constant from cycle to cycle (by definition); skew can be positive (clock and data flowing in the same direction) or negative (clock and data flowing in opposite directions)
 - jitter causes T to change on a cycle-by-cycle basis

Review: Synchronous Timing Basics

Sources of Clock Skew and Jitter in Clock Network



□ Skew

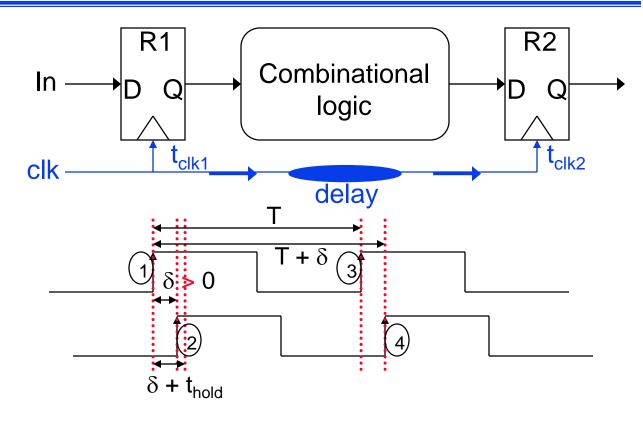
- manufacturing device variations in clock drivers
- interconnect variations
- environmental variations (power supply and temperature)

□ Jitter

- clock generation
- capacitive loading and coupling
- environmental variations (power supply and temperature)

Positive Clock Skew

Clock and data flow in the same direction

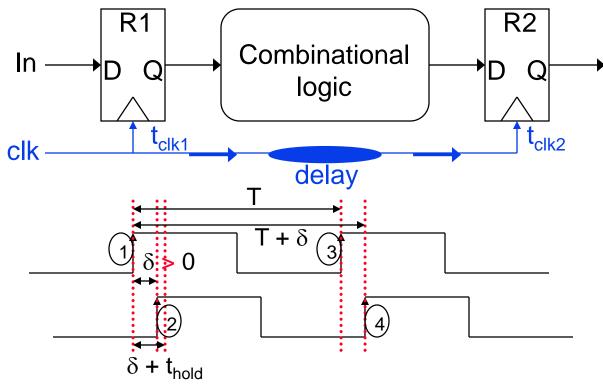


Т

t_{hold}:

Positive Clock Skew

Clock and data flow in the same direction



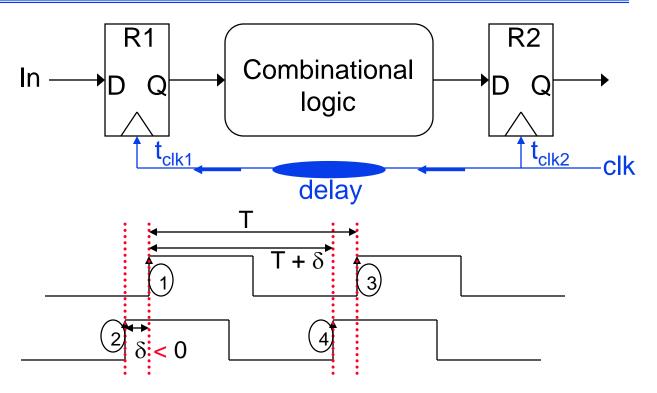
T:
$$T + \delta \ge t_{c-q} + t_{plogic} + t_{su} \quad \text{so} \quad T \ge t_{c-q} + t_{plogic} + t_{su} - \delta$$

$$t_{\text{hold}}$$
: $t_{\text{hold}} + \delta \leq t_{\text{cdlogic}} + t_{\text{cdreg}}$ so $t_{\text{hold}} \leq t_{\text{cdlogic}} + t_{\text{cdreg}} - \delta$

δ > 0: Improves performance, but makes t_{hold} harder to meet. If t_{hold} is not met (race conditions), the circuit malfunctions independent of the clock period!

Negative Clock Skew

Clock and data flow in opposite directions

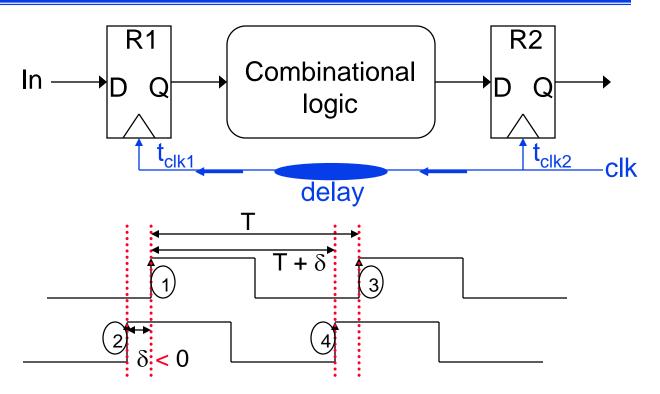


T :

t_{hold}:

Negative Clock Skew

Clock and data flow in opposite directions

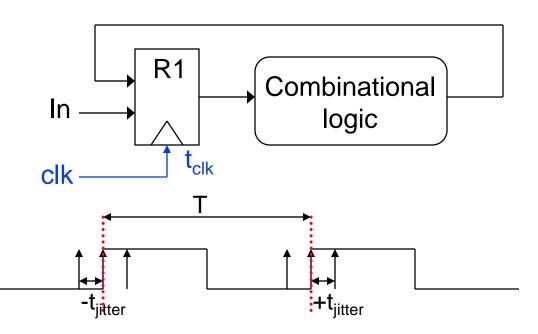


$$\begin{aligned} \text{T:} & \quad \text{T} + \delta \geq t_{\text{c-q}} + t_{\text{plogic}} + t_{\text{su}} \quad \text{so} \quad \text{T} \geq t_{\text{c-q}} + t_{\text{plogic}} + t_{\text{su}} - \delta \\ t_{\text{hold}}: & \quad t_{\text{hold}} + \delta \leq t_{\text{cdlogic}} + t_{\text{cdreg}} \quad \text{so} \quad t_{\text{hold}} \leq t_{\text{cdlogic}} + t_{\text{cdreg}} - \delta \end{aligned}$$

 δ < 0: Degrades performance, but t_{hold} is easier to meet (eliminating race conditions)

Clock Jitter

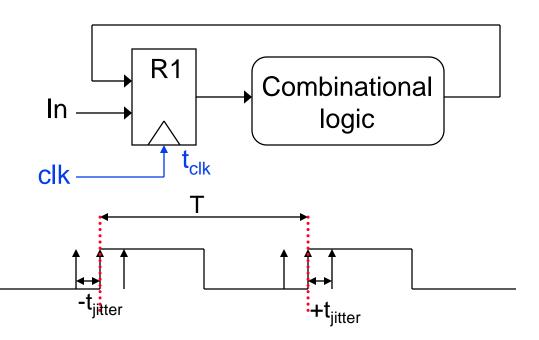
Jitter causes T to vary on a cycle-bycycle basis



T:

Clock Jitter

Jitter causes T to vary on a cycle-bycycle basis

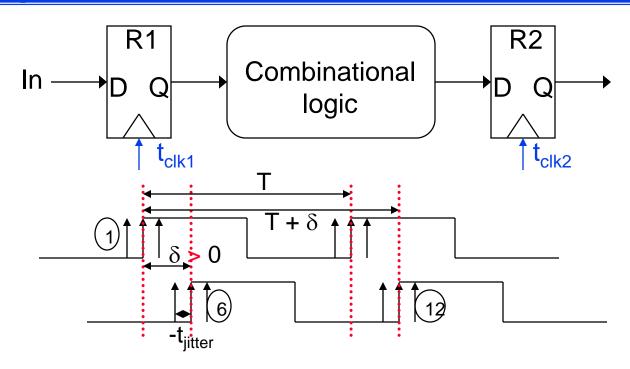


T:
$$T - 2t_{jitter} \ge t_{c-q} + t_{plogic} + t_{su}$$
 so $T \ge t_{c-q} + t_{plogic} + t_{su} + 2t_{jitter}$

Jitter directly reduces the performance of a sequential circuit

Combined Impact of Skew and Jitter

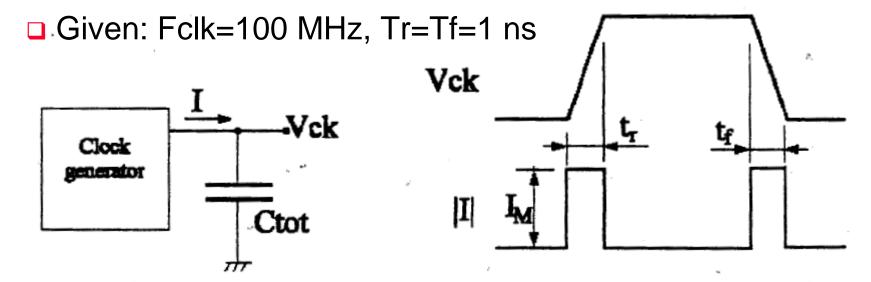
□ Constraints
 on the
 minimum
 clock period
 (δ > 0)



$$T \geq t_{\text{c-q}} + t_{\text{plogic}} + t_{\text{su}} - \delta + 2t_{\text{jitter}} \qquad \qquad t_{\text{hold}} \leq t_{\text{cdlogic}} + t_{\text{cdreg}} - \delta - 2t_{\text{jitter}}$$

Example of a Clock Generator

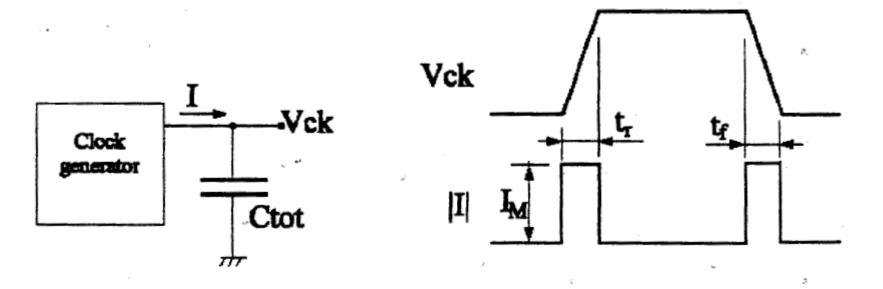
- □ Chip with 10.000 FF
- □ Each FF has a Cin=50 fF for the clock input
- Clock Generator needs to drive Ctot= 500pF



$$I_{M} = Ctot \cdot \frac{\partial Vck}{\partial t}\Big|_{MAX} = C\frac{Vdd}{t_{r}} \cong 2.5A$$

Example of a Clock Generator

- High Power consumption
- Supply line noise
- □ High current density in interconnection (elettromigration!)



$$I_{M} = Ctot \cdot \frac{\partial Vck}{\partial t}\Big|_{M4X} = C\frac{Vdd}{t_{r}} \cong 2.5A$$

Clock Distribution Networks

- Clock skew and jitter can ultimately limit the performance of a digital system, so designing a clock network that minimizes both is important
 - In many high-speed processors, a majority of the dynamic power is dissipated in the clock network.
 - To reduce dynamic power, the clock network must support clock gating (shutting down (disabling the clock) units)

Clock distribution techniques

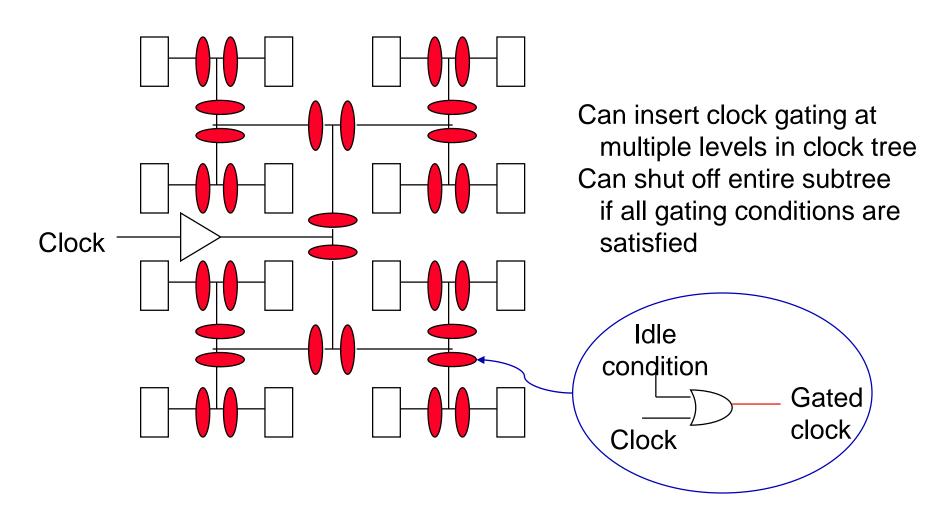
- Balanced paths (H-tree network, matched RC trees)
 - In the ideal case, can eliminate skew
 - Could take multiple cycles for the clock signal to propagate to the leaves of the tree

Clock grids

- Typically used in the final stage of the clock distribution network
- Minimizes absolute delay (not relative delay)

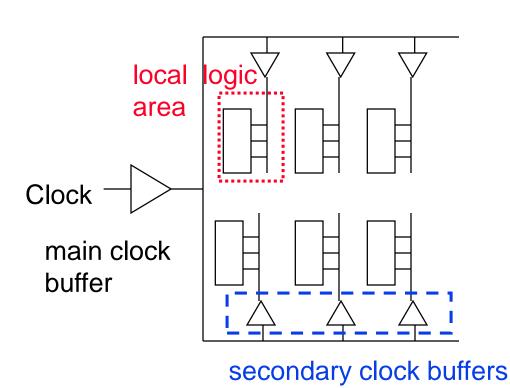
H-Tree Clock Network

□ If the paths are perfectly balanced, clock skew is zero



Clock Grid Network

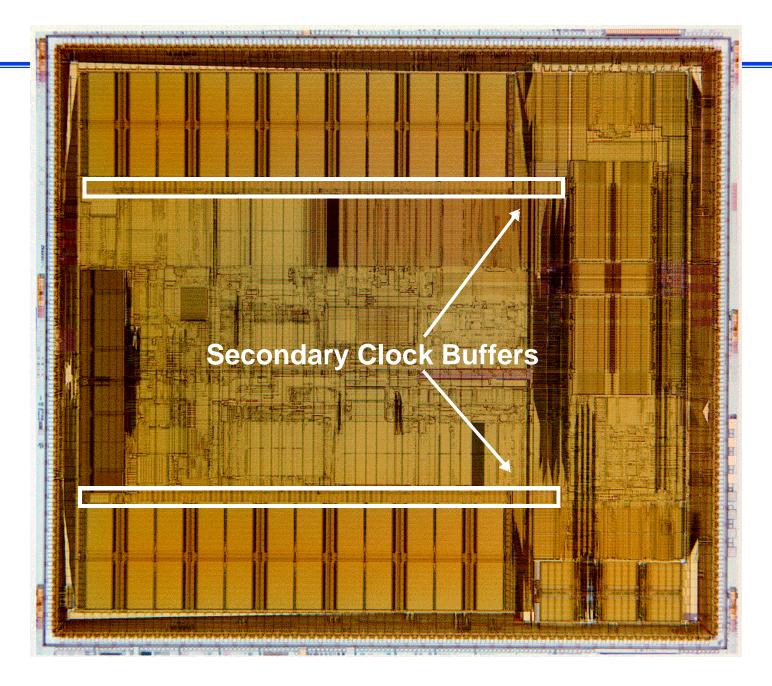
 Distributed buffering reduces absolute delay and makes clock gating easier, but is sensitive to variations in the buffer delay



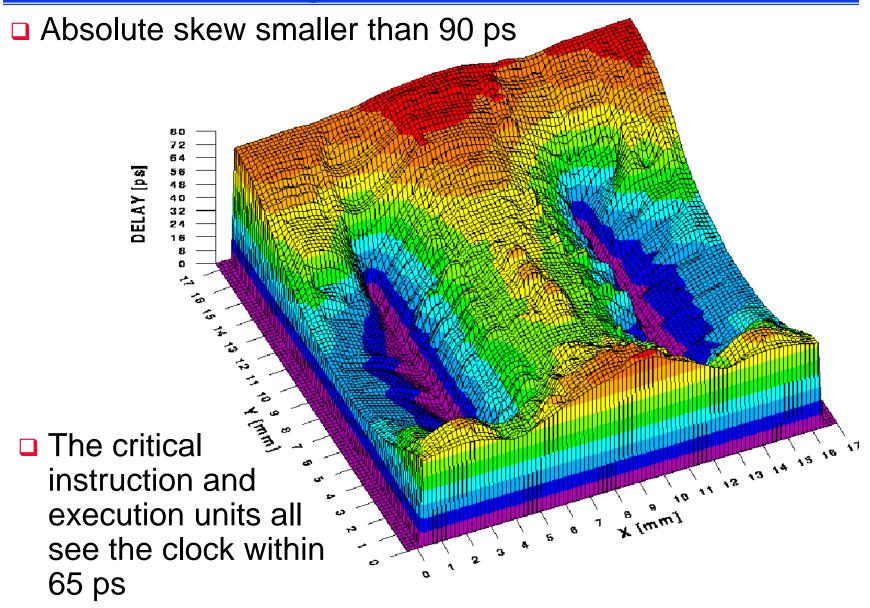
- □ The secondary buffers isolate the local clock nets from the upstream load and amplify the clock signals degraded by the RC network
 - decreases absolute skew
 - gives steeper clocks
- Only have to bound the skew within the local logic area

DEC Alpha 21164 (EV5) Example

- 300 MHz clock (9.3 million transistors on a 16.5x18.1 mm die in 0.5 micron CMOS technology - 4 layer metal)
 - single phase clock
- 3.75 nF total clock load
 - Extensive use of dynamic logic
- 20 W (out of 50) in clock distribution network
- Two level clock distribution
 - Single 6 inverter stage main clock buffer at the center of the chip
 - Secondary clock buffers drive the left and right sides of the clock grid in m3 and m4
- Total equivalent driver size of 58 cm !!



Clock Skew in Alpha Processor



Dealing with Clock Skew and Jitter

- □ To minimize skew, balance clock paths using H-tree or matched-tree clock distribution structures.
- If possible, route data and clock in opposite directions; eliminates races at the cost of performance.
- □ The use of gated clocks to help with dynamic power consumption make jitter worse.
- □ Shield clock wires (route power lines V_{DD} or GND next to clock lines) to minimize/eliminate coupling with neighboring signal nets.
- Use dummy fills to reduce skew by reducing variations in interconnect capacitances due to interlayer dielectric thickness variations.
- Beware of temperature and supply rail variations and their effects on skew and jitter. *Power supply noise fundamentally limits the performance of clock networks.*

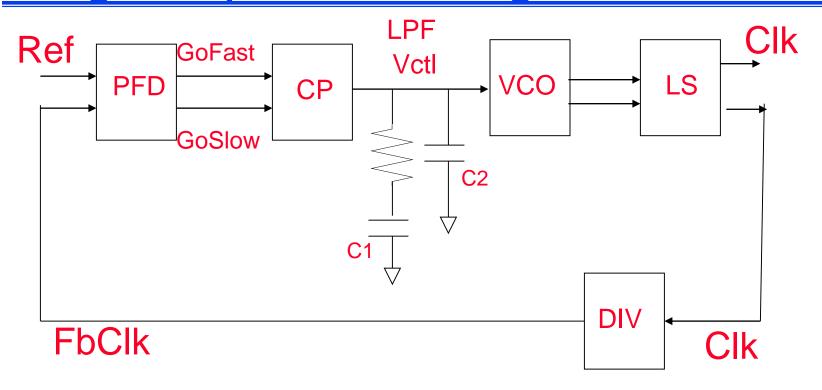
What is a PLL?

□ A PLL is a negative feedback system where an oscillatorgenerated signal is phase and frequency locked to a reference signal.

How are PLL's Used?

- Frequency Synthesis (e.g. generating a 1 GHz clock from a 100 MHz reference)
- Skew Cancellation (e.g. phase-aligning an internal clock to the IO clock) (May use a DLL instead)
- Extracting a clock from a random data stream (e.g. seriallink receiver)

Charge-Pump PLL Block Diagram



- Phase-Frequency Detector (*PFD*)
- Voltage-Controlled Oscillator (VCO)

Charge-Pump (CP)

VCO Level-Shifter (LS)

■ Low-Pass Filter (*LPF*)

Feedback Divider (FBDIV)

Components in a Nutshell

- PFD: outputs digital pulse whose width is proportional to phase error
- CP: converts digital error pulse to analog error current
- LPF: integrates (and low-pass filters) error current to generate VCO control voltage
- VCO: low-swing oscillator with frequency proportional to control voltage
- LS: amplifies VCO levels to full-swing
- □ DIV: divides VCO clock to generate FBCLK clock

System Timing Constraints

